

**Notice of References Cited**

Application/Control No.

10/621,238

Applicant(s)/Patent Under  
Reexamination  
NAKAHARA ET AL.

Examiner

Richard L. Chiesa

Art Unit

1724

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2,692,657	10-1954	Barton, Edmund	95/282
	B	US-2,762,449	09-1956	Sweeney, Maxwell P.	95/229
	C	US-3,299,647	01-1967	Roosendaal et al.	62/637
	D	US-4,252,545	02-1981	Haferkorn, Herbert	95/271
	E	US-4,391,617	07-1983	Way, Peter F.	95/290
	F	US-4,696,683	09-1987	Vitovec et al.	95/268
	G	US-4,725,291	02-1988	Ueoka et al.	95/290
	H	US-6,638,345	10-2003	Takahashi et al.	95/288
	I	US-2002/0053288	05-2002	Takahashi et al.	95/288
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	10-279522	10-1998	Japan	---	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.